

SEARCHED			
Class	Sub.	Date	Exmr.
369	44.23 112.12 112.15 112.24 44.32 53.28	11/21/03	fla
369	44.32 44.23 53.28 112.12 112.15 112.24	5/14/04	fla
updated above		12/21/04	fla

INTERFERENCE SEARCHED			
Class	Sub.	Date	Exmr.
369	44.23 44.41 112.12 44.32 53.28	12/21/04	fla

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	Date	Exmr.
aberration or aberration or aberration or aberration measure/measurement defect reflected split/splitter difference between signals focal shift	11/21/03	fla
thickness sensor Pt Young provided Subclasser	11/21/03	fla
performed more extensive search using listed sub- classes. see attached EAST search	5/14/04	fla
in addition, also searched 44.41 (arithmetic operation)	5/14/04	fla
see updated east search	12/21/04	fla

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